

DOSEMI**IGBT****DG50A07EBFS****750V/50A IGBT with Diode**

General Description

DOSEMI IGBT Power Discrete provides ultra low conduction loss as well as low switching loss. They are designed for the applications such as hybrid and electric vehicle.

Features

- Low $V_{CE(sat)}$ Fast IGBT technology
- Low switching loss
- Maximum junction temperature 175°C
- $V_{CE(sat)}$ with positive temperature coefficient

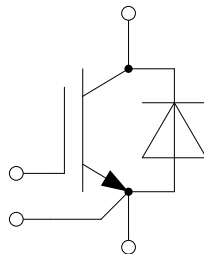
Typical Applications

- DC/DC converter
- On board charger (OBC)
- Inductive charger systems

Validation

- Qualified according to AEC-Q101
- Qualified for Automotive application

Equivalent Circuit Schematic



Type	Package	Marking	Shipping
DG50A07EBFS	TO-263-7L	DG50A07EBFS	30Units/Tube

Absolute Maximum Ratings $T_C=25^{\circ}\text{C}$ unless otherwise noted**IGBT**

Symbol	Description	Values	Unit
V_{CES}	Collector-Emitter Voltage	750	V
V_{GES}	Gate-Emitter Voltage Transient Gate-Emitter Voltage	± 20 ± 30	V
I_C	Collector Current @ $T_C=25^{\circ}\text{C}$ @ $T_C=100^{\circ}\text{C}$	85 50	A
I_{CM}	Pulsed Collector Current t_p limited by T_{vjmax}	150	A
P_D	Maximum Power Dissipation @ $T_{vj}=175^{\circ}\text{C}$	272	W

Diode

Symbol	Description	Values	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	750	V
I_F	Diode Continuous Forward Current @ $T_C=25^{\circ}\text{C}$ @ $T_C=100^{\circ}\text{C}$	85 50	A
I_{FM}	Diode Pulsed Current t_p limited by T_{vjmax}	150	A

Discrete

Symbol	Description	Values	Unit
T_{vjop}	Operating Junction Temperature	-40 to +175	$^{\circ}\text{C}$
T_{STG}	Storage Temperature Range	-55 to +150	$^{\circ}\text{C}$
T_S	Soldering Temperature, 1.6mm from case for 10s	260	$^{\circ}\text{C}$
M	Mounting Torque, Screw M3	0.6	N.m

IGBT Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{CE(sat)}$	Collector to Emitter Saturation Voltage	$I_C=50\text{A}, V_{GE}=15\text{V}, T_{vj}=25^{\circ}\text{C}$		1.55	2.00	V
		$I_C=50\text{A}, V_{GE}=15\text{V}, T_{vj}=150^{\circ}\text{C}$		1.90		
		$I_C=50\text{A}, V_{GE}=15\text{V}, T_{vj}=175^{\circ}\text{C}$		2.00		
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	$I_C=1.0\text{mA}, V_{CE}=V_{GE}, T_{vj}=25^{\circ}\text{C}$	3.5	4.0	4.5	V
I_{CES}	Collector Cut-Off Current	$V_{CE}=V_{CES}, V_{GE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$			200	μA
I_{GES}	Gate-Emitter Leakage Current	$V_{GE}=V_{GES}, V_{CE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$			100	nA
R_{Gint}	Internal Gate Resistance			0		Ω
C_{ies}	Input Capacitance	$V_{CE}=25\text{V}, f=100\text{kHz}, V_{GE}=0\text{V}$		1.94		nF
C_{oes}	Output Capacitance			0.06		nF
C_{res}	Reverse Transfer Capacitance			0.01		nF
Q_G	Gate Charge	$V_{GE}=-15\dots+15\text{V}$		0.12		μC
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=400\text{V}, I_C=50\text{A}, R_G=8.2\Omega, L_S=40\text{nH}, V_{GE}=\pm 15\text{V}, T_{vj}=25^{\circ}\text{C}$		15		ns
t_r	Rise Time			46		ns
$t_{d(off)}$	Turn-Off Delay Time			75		ns
t_f	Fall Time			20		ns
E_{on}	Turn-On Switching Loss			1.76		mJ
E_{off}	Turn-Off Switching Loss			0.59		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=400\text{V}, I_C=50\text{A}, R_G=8.2\Omega, L_S=40\text{nH}, V_{GE}=\pm 15\text{V}, T_{vj}=150^{\circ}\text{C}$		16		ns
t_r	Rise Time			46		ns
$t_{d(off)}$	Turn-Off Delay Time			95		ns
t_f	Fall Time			24		ns
E_{on}	Turn-On Switching Loss			2.27		mJ
E_{off}	Turn-Off Switching Loss			0.78		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=400\text{V}, I_C=50\text{A}, R_G=8.2\Omega, L_S=40\text{nH}, V_{GE}=\pm 15\text{V}, T_{vj}=175^{\circ}\text{C}$		17		ns
t_r	Rise Time			45		ns
$t_{d(off)}$	Turn-Off Delay Time			99		ns
t_f	Fall Time			27		ns
E_{on}	Turn-On Switching Loss			2.44		mJ
E_{off}	Turn-Off Switching Loss			0.92		mJ

Diode Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_F	Diode Forward Voltage	$I_C=50\text{A}, V_{GE}=0\text{V}, T_{vj}=25^{\circ}\text{C}$		1.80	2.25	V
		$I_C=50\text{A}, V_{GE}=0\text{V}, T_{vj}=150^{\circ}\text{C}$		1.75		
		$I_C=50\text{A}, V_{GE}=0\text{V}, T_{vj}=175^{\circ}\text{C}$		1.70		
t_{rr}	Diode Reverse Recovery Time	$V_R=400\text{V}, I_F=50\text{A},$ $-di/dt=1300\text{A}/\mu\text{s}, L_s=40\text{nH},$ $V_{GE}=-15\text{V}, T_{vj}=25^{\circ}\text{C}$		74		ns
Q_r	Recovered Charge			1.22		μC
I_{RM}	Peak Reverse Recovery Current			24		A
E_{rec}	Reverse Recovery Energy			0.18		mJ
t_{rr}	Diode Reverse Recovery Time	$V_R=400\text{V}, I_F=50\text{A},$ $-di/dt=840\text{A}/\mu\text{s}, L_s=40\text{nH},$ $V_{GE}=-15\text{V}, T_{vj}=150^{\circ}\text{C}$		138		ns
Q_r	Recovered Charge			2.52		μC
I_{RM}	Peak Reverse Recovery Current			31		A
E_{rec}	Reverse Recovery Energy			0.50		mJ
t_{rr}	Diode Reverse Recovery Time	$V_R=400\text{V}, I_F=50\text{A},$ $-di/dt=840\text{A}/\mu\text{s}, L_s=40\text{nH},$ $V_{GE}=-15\text{V}, T_{vj}=175^{\circ}\text{C}$		153		ns
Q_r	Recovered Charge			2.89		μC
I_{RM}	Peak Reverse Recovery Current			33		A
E_{rec}	Reverse Recovery Energy			0.59		mJ

Discrete Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Min.	Typ.	Max.	Unit
R_{thJC}	Junction-to-Case (per IGBT)			0.550	K/W
	Junction-to-Case (per Diode)			0.657	
R_{thJA}	Junction-to-Ambient		40		K/W

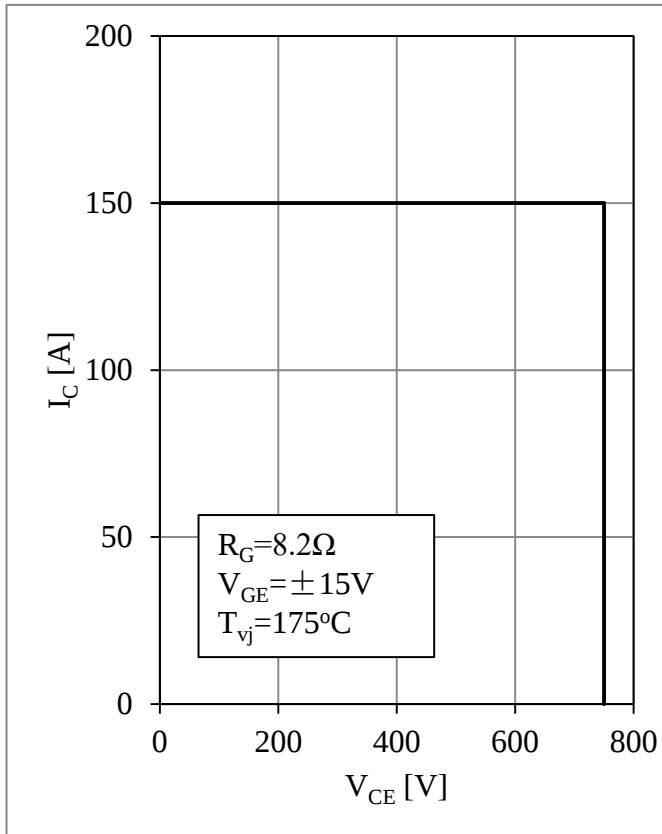


Fig 1. RBSOA

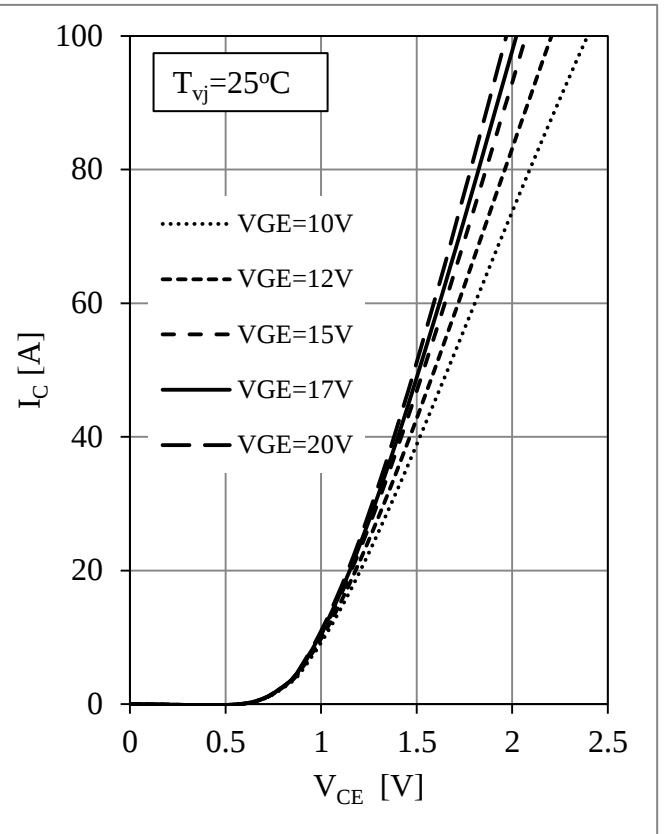


Fig 2. IGBT Output Characteristics

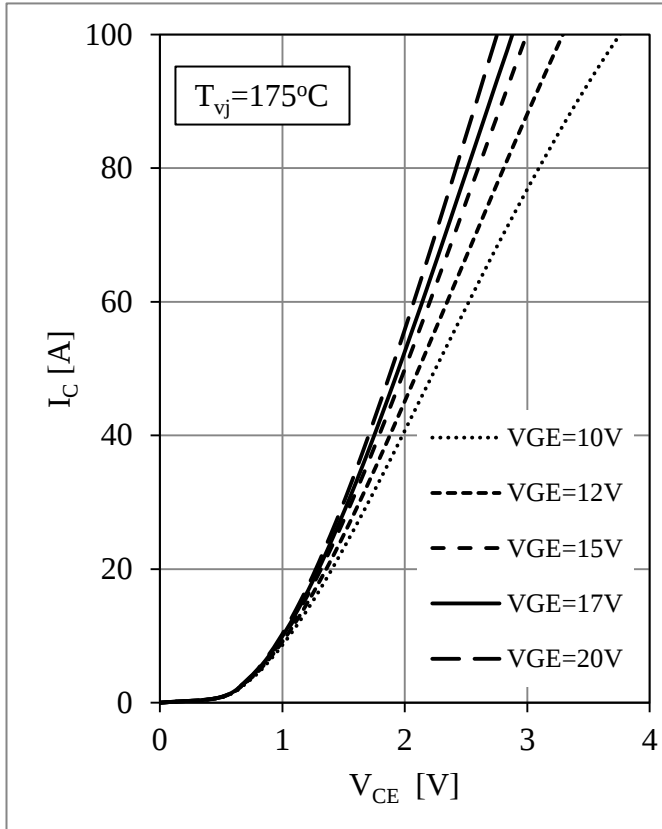


Fig 3. IGBT Output Characteristics

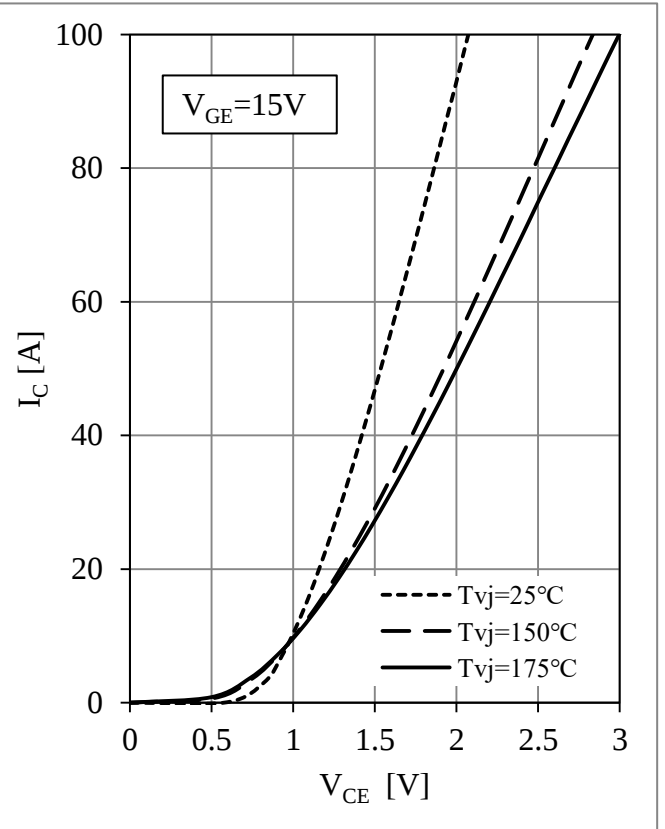


Fig 4. IGBT Output Characteristics

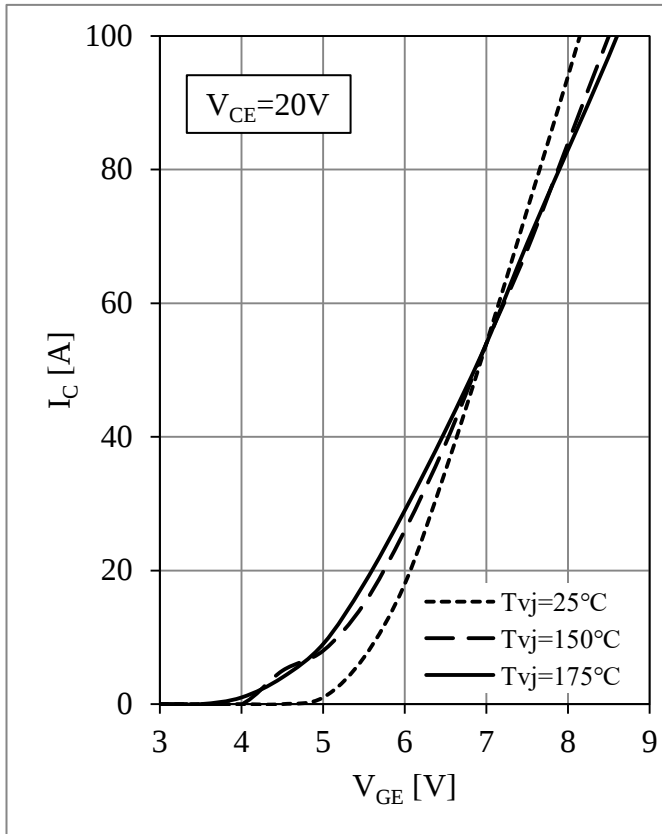
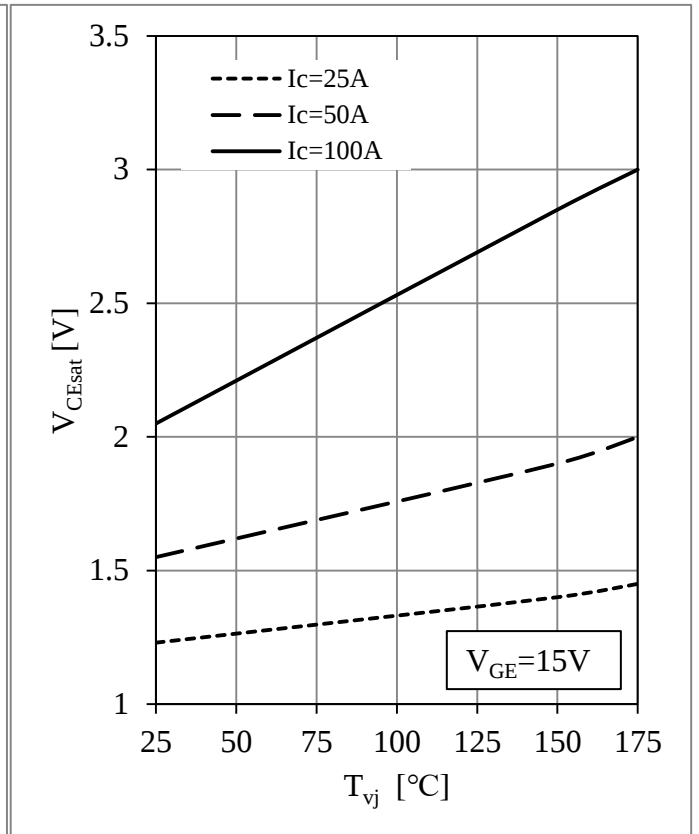
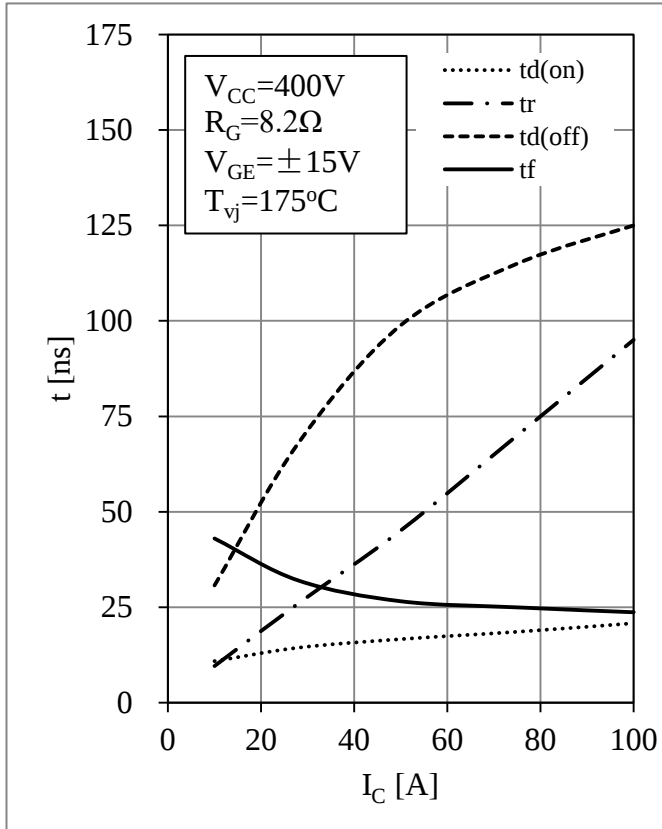
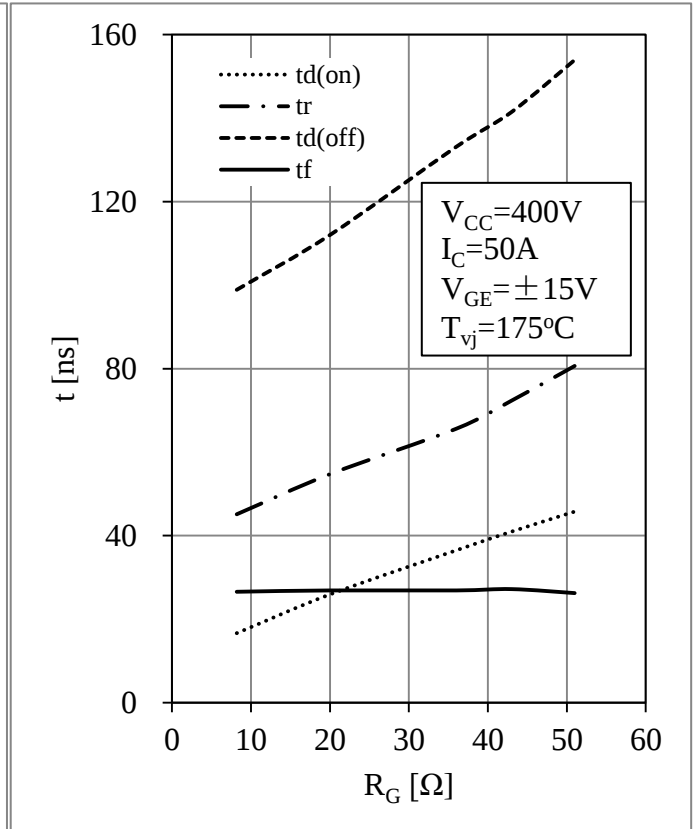
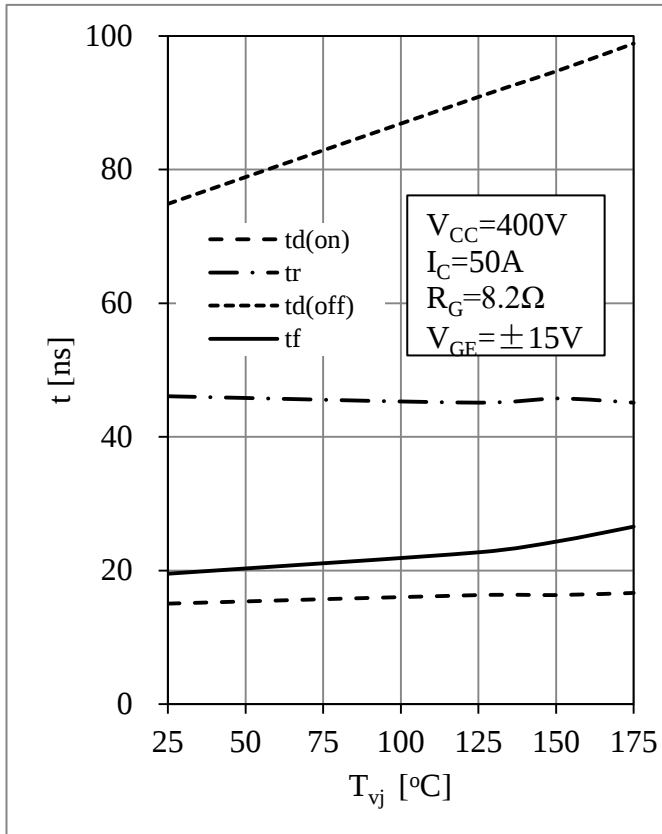
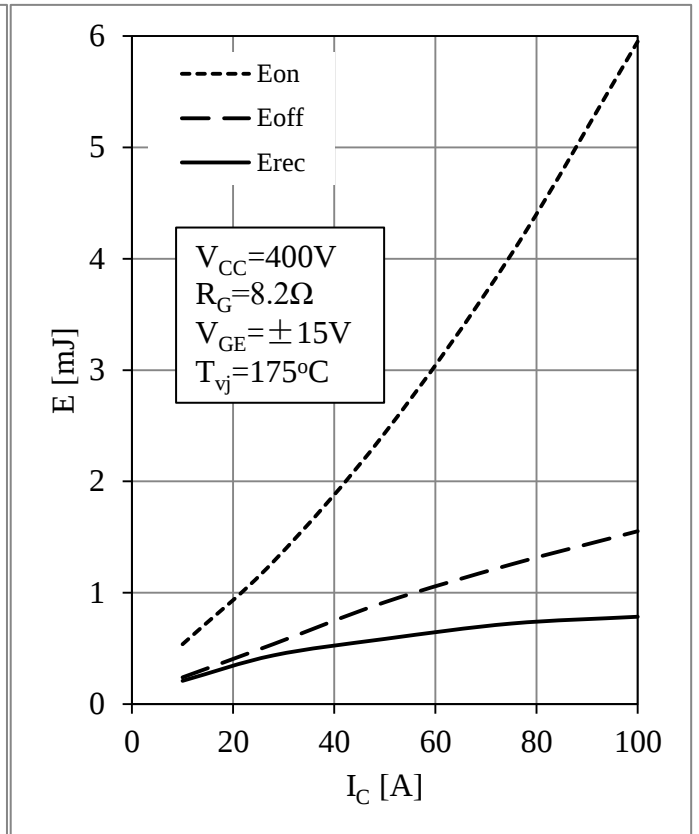
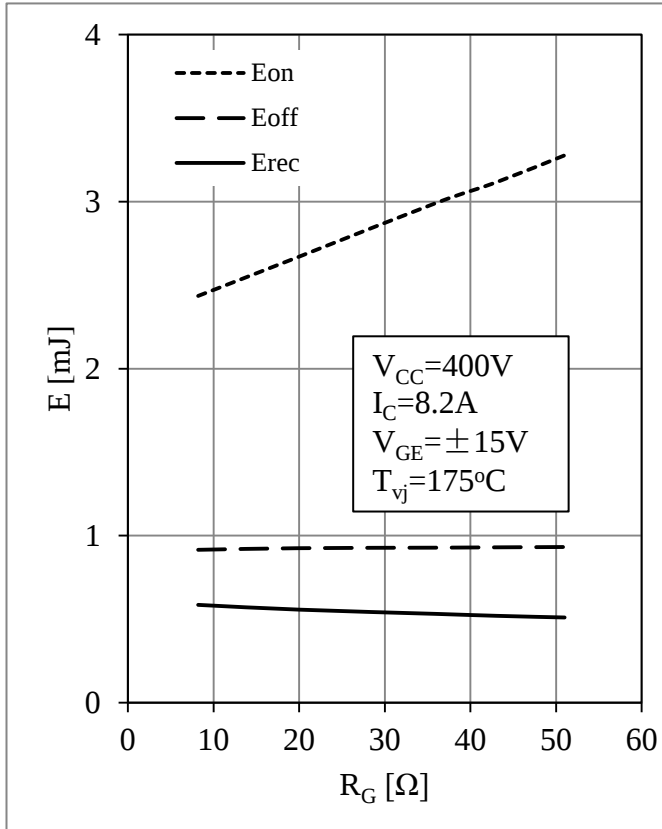
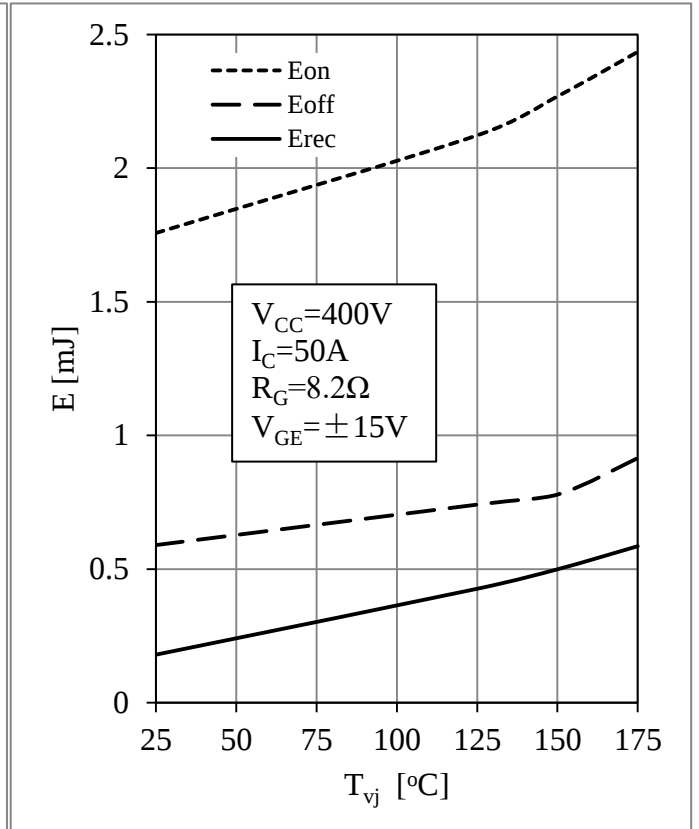


Fig 5. IGBT Transfer Characteristics

Fig 6. Collector-emitter saturation voltage vs. T_{vj} Fig 7. IGBT Switching Times vs. I_C Fig 8. IGBT Switching Times vs. R_G

Fig 9. IGBT Switching Times vs. T_{vj} Fig 10. Switching Energy Loss vs. I_C Fig 11. Switching Energy Loss vs. R_G Fig 12. Switching Energy Loss vs. T_{vj}

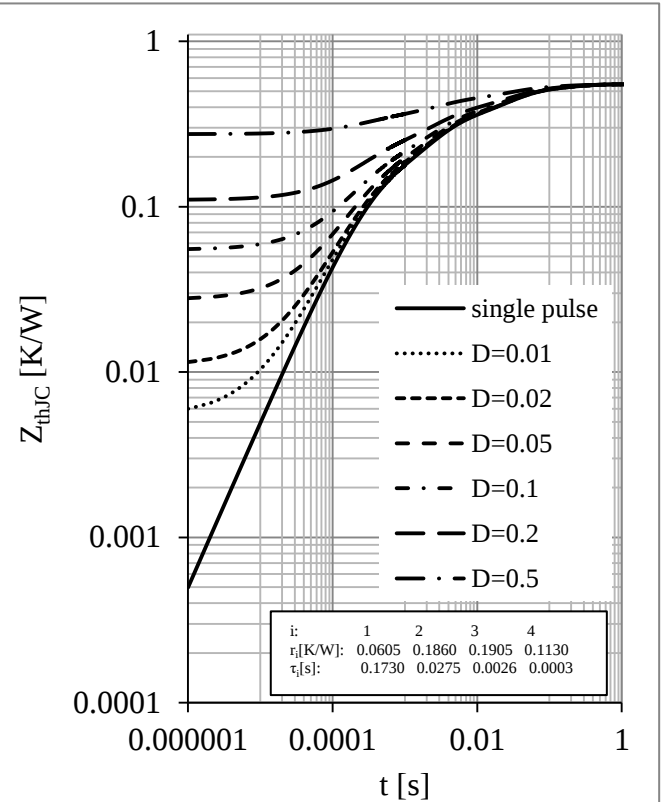
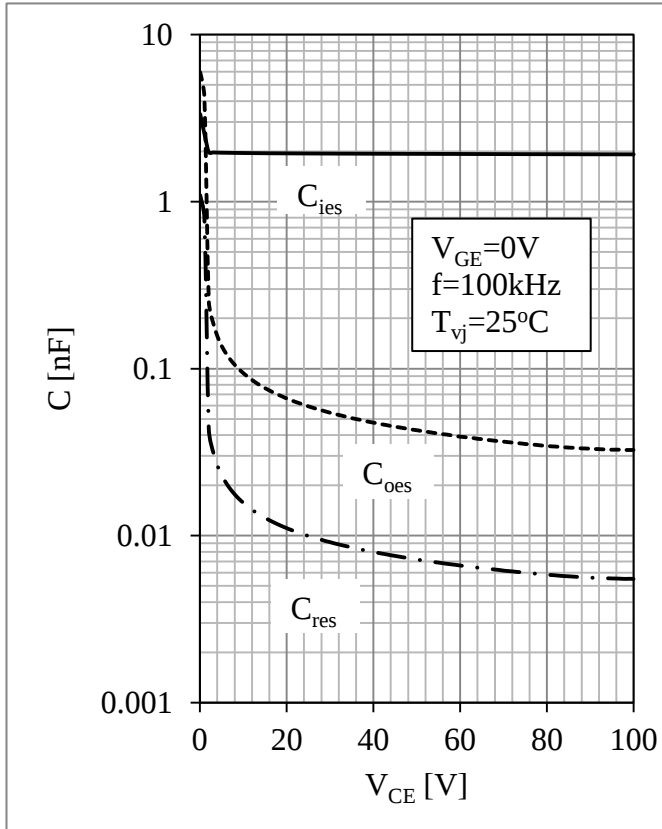
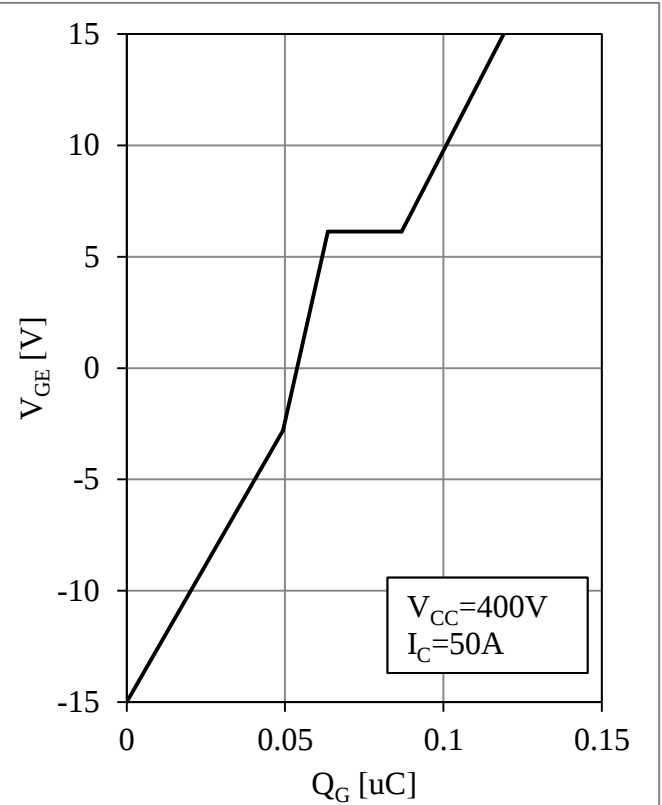
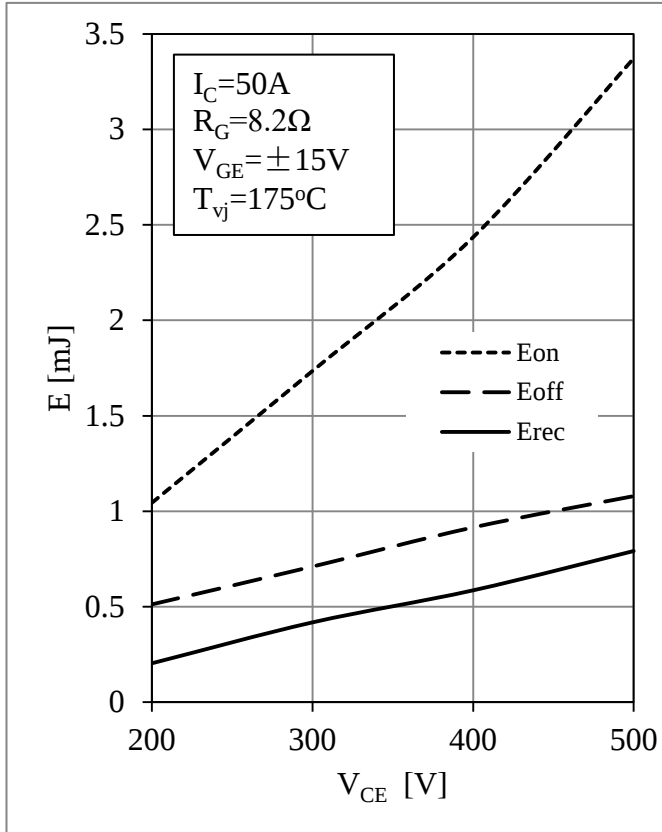


Fig 15. IGBT Capacity Characteristic

Fig 16. IGBT Transient Thermal Impedance

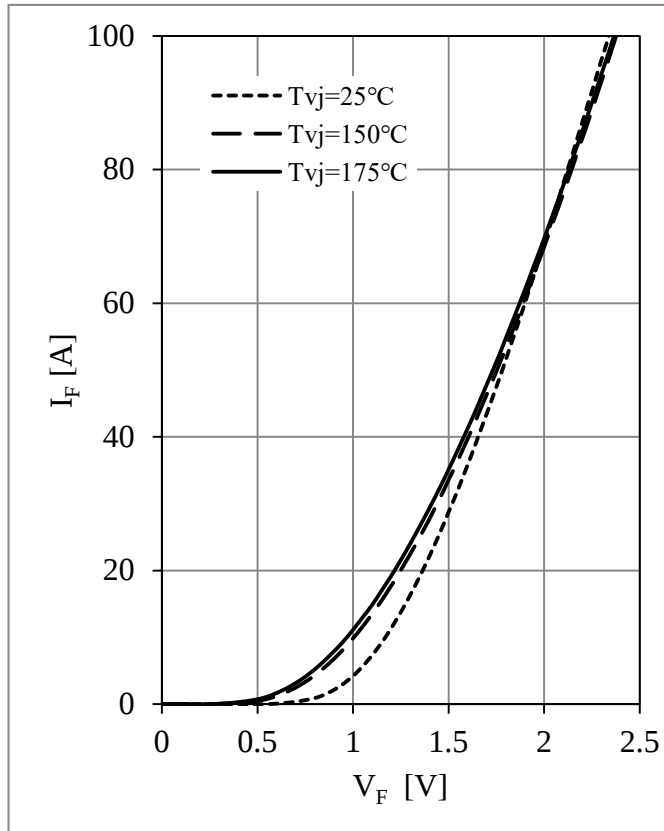
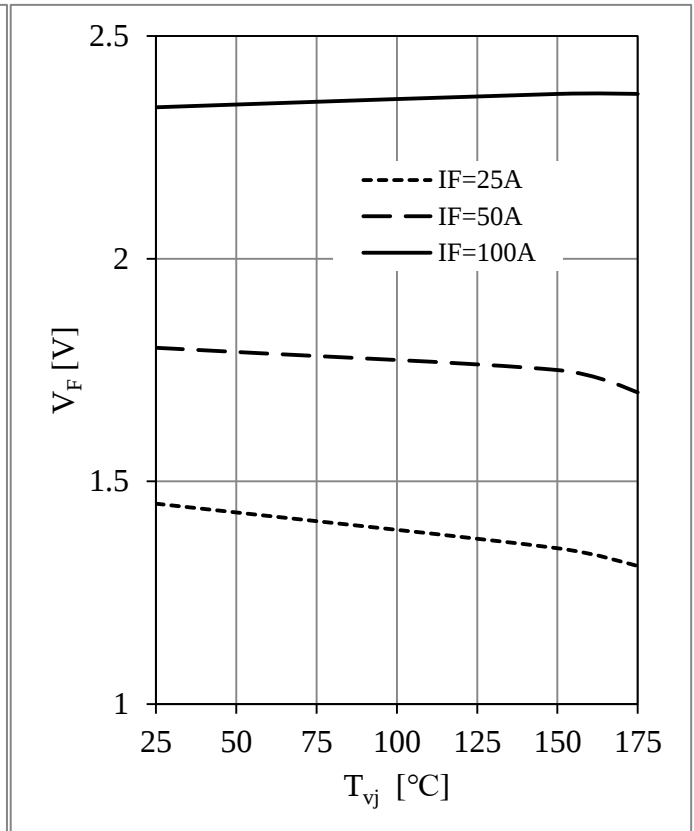
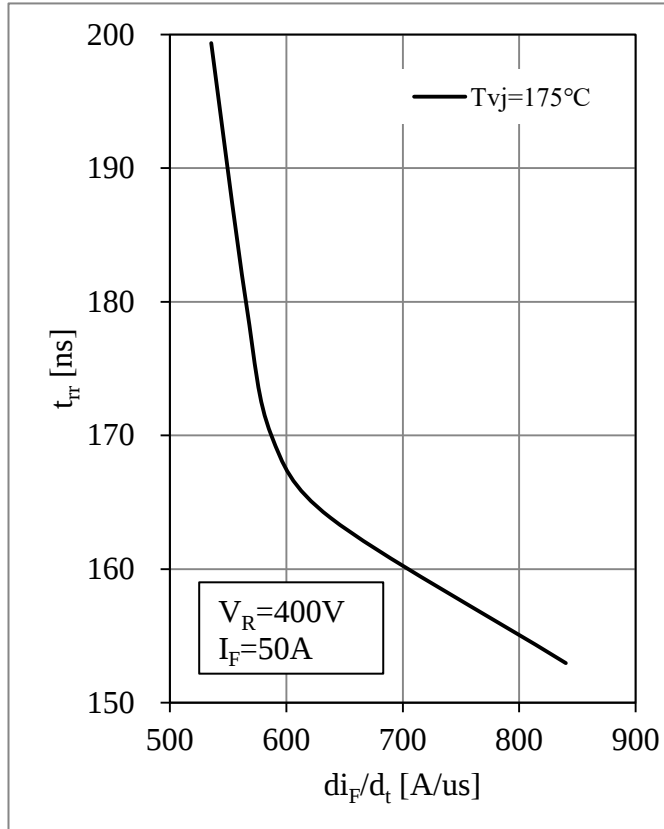
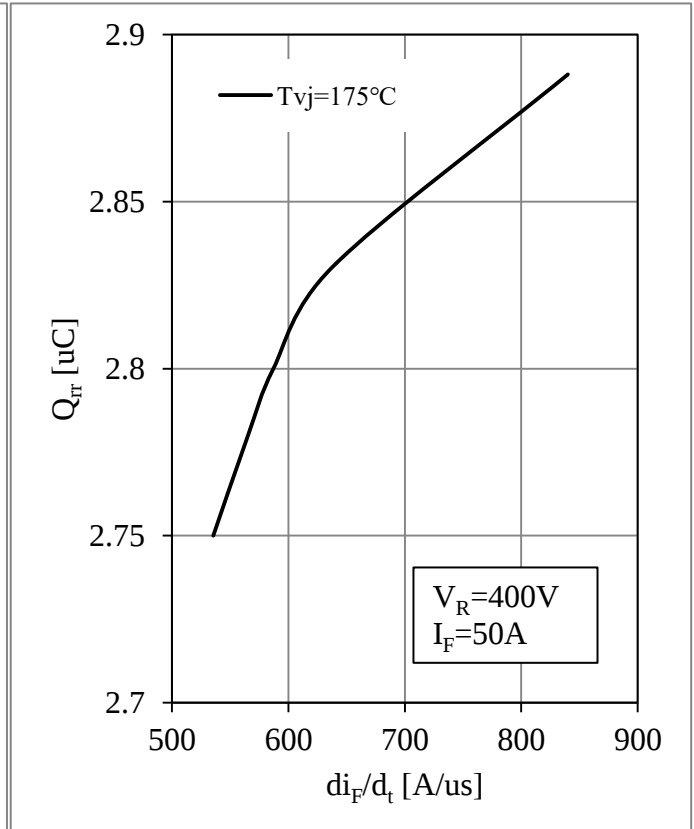


Fig 17. Diode Forward Characteristics

Fig 18. Diode Forward Voltage vs. T_{vj} Fig 19. Reverse Recovery Time vs. di_F/d_t Fig 20. Reverse Recovery Charge vs. di_F/d_t

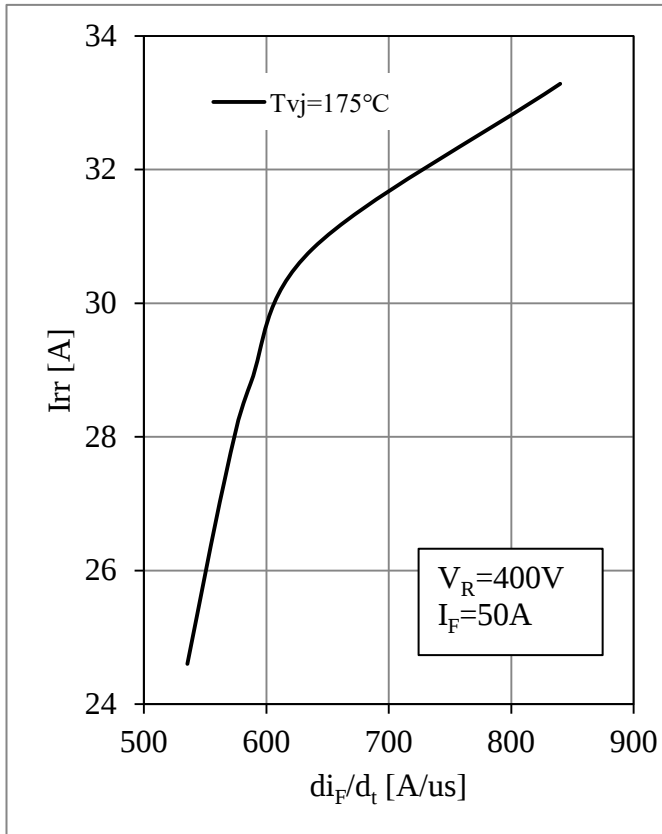
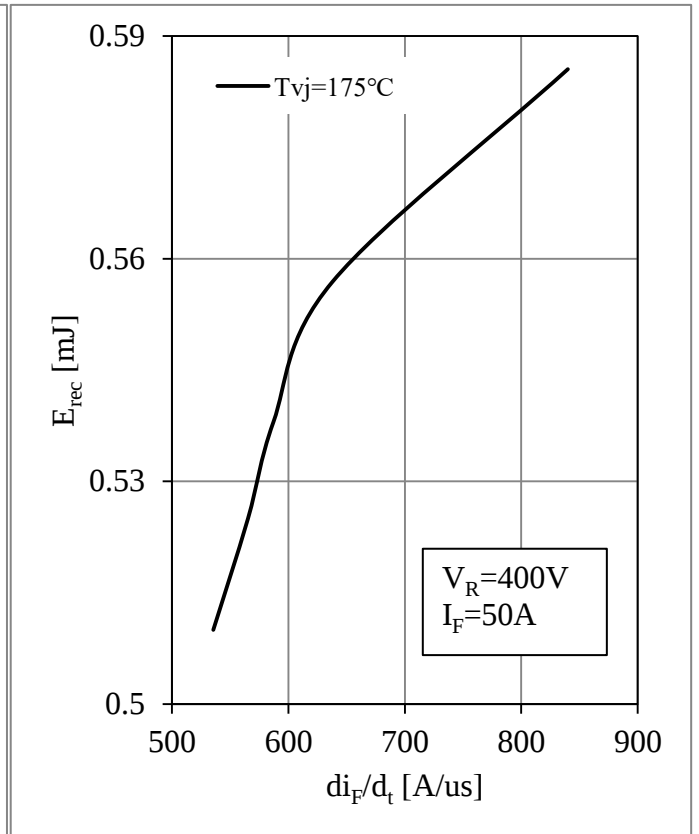
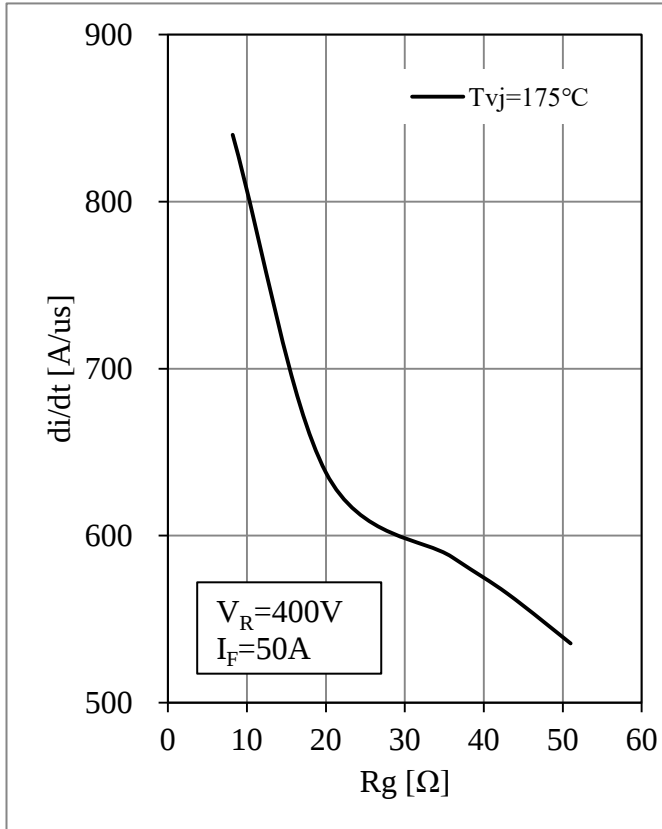
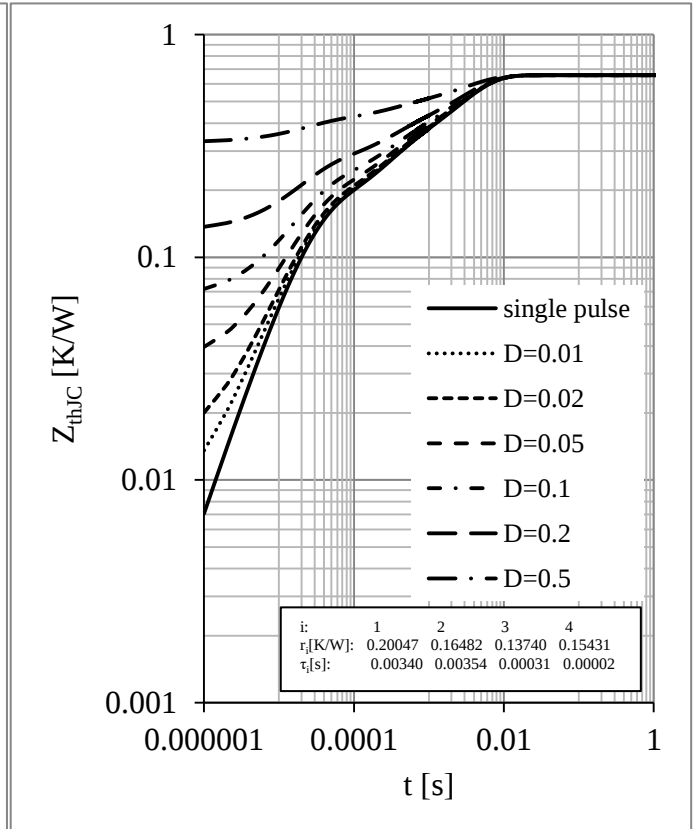
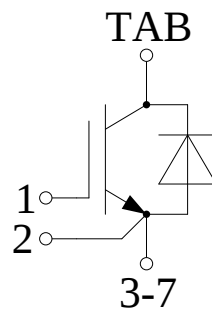
Fig 21. Reverse Recovery Current vs. di_F/d_t Fig 22. Reverse Energy Losses vs. di_F/d_t Fig 23. di_F/d_t vs. R_G 

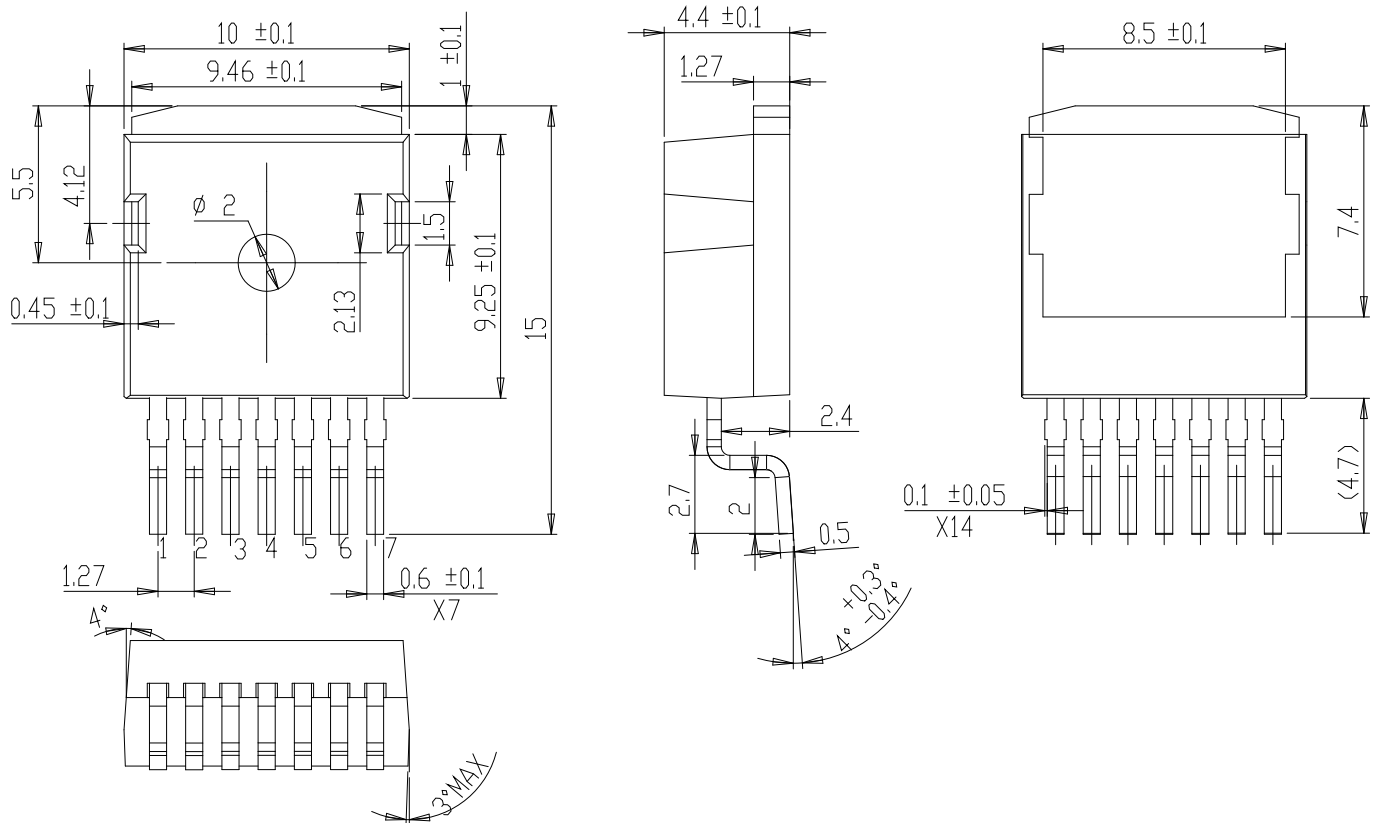
Fig 24. Diode Transient Thermal Impedance

Circuit Schematic



Package Dimensions

Dimensions in Millimeters



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